

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/783,703	LIN, CHIH-I
<b>Examiner</b>	<b>Art Unit</b>	
LAM T. MAI	2819	

**SEARCHED**

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
<i>as</i> US-PGPUB		10/13/2005	LM